

L Number	Hits	Search Text	DB	Time stamp
2	23	gaku with kamitani	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:15
3	85	preparing and measuring and obtaining and correcting and impedance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:20
4	1	(gaku with kamitani) and (preparing and measuring and obtaining and correcting and impedance)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:16
6	2319	preparing and measuring and obtaining and correcting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:16
7	3	(gaku with kamitani) and (preparing and measuring and obtaining and correcting)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:17
8	1246	preparing and measuring and obtaining and correcting and (resistance resistive resistor impedance)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:21
9	3	(gaku with kamitani) and (preparing and measuring and obtaining and correcting and (resistance resistive resistor impedance))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:39
11	1	(measurement with error) and (chip (electronic with (device component))) and (correction with data with (impedance resistance resistor)) and ((measuring with device) meter) and ((expression equation relationship) with actual with standard) and ((correcting correction correct) with (impedance resistance resistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:47
13	1	(measurement with error) and (chip (electronic with (device component))) and ((correction correcting) with data with (impedance resistance resistor)) and ((measuring with device) meter) and ((expression equation relationship) with actual with standard) and ((correcting correction correct) with (impedance resistance resistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:49
12	2	((correction correcting) with data with (impedance resistance resistor)) and ((measuring with device) meter) and ((expression equation relationship) with actual with standard) and ((correcting correction correct) with (impedance resistance resistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:47
14	23	(measurement with error) and (chip (electronic with (device component))) and ((correction correcting) with data with (impedance resistance resistor)) and ((measuring with device) meter) and ((expression equation relationship) and ((correcting correction correct) with (impedance resistance resistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:54

15	23	((measurement with error) and (chip (electronic with (device component))) and ((correction correcting) with data with (impedance resistance resistor)) and ((measuring with device) meter) and ((expression equation relation relationship)) and ((correcting correction correct) with (impedance resistance resistor)) and ((impedance resistance resistor) with (error correcting correction))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/12 08:55
----	----	--	---	---------------------